Notice of References Cited Application/Control No. 10/529,808 Examiner Megann E. Vaughn Applicant(s)/Patent Under Reexamination SEBACHER ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,765,948	06-1998	Sai, Yukio	374/161
*	В	US-5,217,306	06-1993	Wada, Fumio	374/161
*	С	US-2003/0021528	01-2003	Fredin et al.	385/31
*	D	US-5,592,282	01-1997	Hartog, Arthur H.	356/44
*	Ε	US-4,823,166	04-1989	Hartog et al.	356/44
*	F	US-5,113,277	05-1992	Ozawa et al.	398/79
*	Ð	US-5,638,172	06-1997	Alsmeyer et al.	356/301
*	I	US-5,820,265	10-1998	Kleinerman, Marcos Y.	374/137
*	1	US-5,113,277	05-1992	Ozawa et al.	398/79
	٦	US-			
	Κ	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	2					
	0					
	Р					
	α					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.